

Search Notes

Application/Control No.

10/517,316

Examiner

Nam V. Nguyen

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
340	10.1	11/1/07	NN
340	10.2	11/1/2007	NN
340	10.31	11/1/2007	NN
340	10.51	11/1/2007	NN
340	10.32	11/1/2007	NN
340	10.42	11/1/2007	NN
340	572.4	11/1/2007	NN
340	825.69	11/1/2007	NN
340	825.72	11/1/2007	NN
342	42, 44	11/1/2007	NN
235	375	11/1/2007	NN
370	437	11/1/2007	NN

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search EAST: USPAT; US-PUB; EPO; JPO and Derwent.	11/1/07	NN
Search TERMS: rfids, tags or transponders with range distance readings, zones, and twice.	11/1/2007	NN